

Search Notes



Application/Control No.

10/651,663

Examiner

Yuwen Pan

Applicant(s)/Patent under Reexamination

XIE, FEI

Art Unit

2682

SEARCHED

Class	Subclass	Date	Examiner
415	412.1 412.2 550.1	10/12/05	yw
	556.2		
707	205		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Lewis West	10/12/05	yw